



High Performance, Highest Capacity Flash and Memory TDBI System

For burning-in and testing state-of-the-art memory devices
including Flash, SDR, DDR, RDRAM, Static, Applications Specific
and Embedded memories



System Features

- Burns-in and tests today's and tomorrow's memories
- 260 channels per PTB slot
- 128 I/Os per PTB slot
- Up to 16,384 device I/Os per PTB
- Approximately 12,480 devices per system
- Full algorithmic pattern generator
- Address and data scrambling
- 20MHz Pattern Generator
- Vbump
- 32 timing sets, on-the-fly

Software Features

- Multi-user, multi-tasking operating system
- Graphical test program development interface
- Integrated database
- Network server with TCP/IP communications

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